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January 2002  
 Revised September 2002

## FIN1101

### LVDS Single Port High Speed Repeater

#### General Description

This single port repeater is designed for high speed interconnects utilizing Low Voltage Differential Signaling (LVDS) technology. It accepts and outputs LVDS levels with a typical differential output swing of 330 mV which provides low EMI at ultra low power dissipation even at high frequencies. It can directly accept multiple differential I/O including: LVPECL, HSTL, and SSTL-2 for translating directly to LVDS.

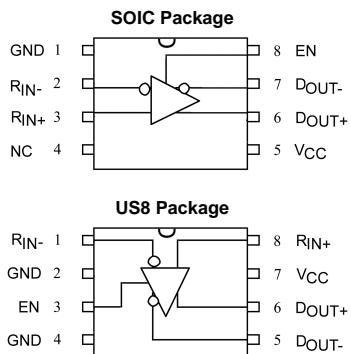
#### Features

- Up to 1.6 Gb/s full differential path
- 3.5 ps max random jitter and 135 ps max deterministic jitter
- 3.3V power supply operation
- Wide rail-to-rail common mode range
- Ultra low power consumption
- LVDS receiver inputs accept LVPECL, HSTL, and SSTL-2 directly
- Power off protection
- 7 kV HBM ESD protection (all pins)
- Meets or exceed the TA/EIA-644-A LVDS standard
- Packaged in 8-pin SOIC and US8
- Open circuit fail safe protection

#### Ordering Code:

Order Number	Package Number	Package Description
FIN1101M	M08A	8-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow [TUBE]
FIN1101MX	M08A	8-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow [TAPE and REEL]
FIN1101K8X	MAB08A	8-Lead US8, JEDEC MO-187, Variation CA 3.1mm Wide [TAPE and REEL]

#### Connection Diagrams



#### Pin Descriptions

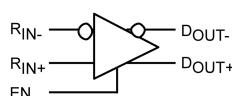
Pin Name	Description
R <sub>IN+</sub>	Non-Inverting LVDS Inputs
R <sub>IN-</sub>	Inverting LVDS Inputs
D <sub>OUT+</sub>	Non-Inverting Driver Outputs
D <sub>OUT-</sub>	Inverting Driver Outputs
EN	Driver Enable Pin
V <sub>CC</sub>	Power Supply
GND	Ground

#### Function Table

EN	Inputs		Outputs	
	R <sub>IN+</sub>	R <sub>IN-</sub>	D <sub>OUT+</sub>	D <sub>OUT-</sub>
H	H	L	H	L
H	L	H	L	H
H	Fail Safe Case		H	L
L	X	X	Z	Z

H = HIGH Logic Level      L = LOW Logic Level  
 X = Don't Care      Z = High Impedance

#### Functional Diagram



**FIN1101**

<b>Absolute Maximum Ratings</b> <sup>(Note 1)</sup>		<b>Recommended Operating Conditions</b>				
Supply Voltage ( $V_{CC}$ )	-0.5V to +4.6V	Supply Voltage ( $V_{CC}$ )	3.0V to 3.6V			
LVDS DC Input Voltage ( $V_{IN}$ )	-0.5V to +4.6V	Operating Temperature ( $T_A$ )	-40°C to +85°C			
LVDS DC Output Voltage ( $V_{OUT}$ )	-0.5V to +4.6V	Magnitude of Input				
Driver Short Circuit Current ( $I_{OSD}$ )	Continuous 10 mA	Differential Voltage ( $ V_{ID} $ )	100 mV to $V_{CC}$			
Storage Temperature Range ( $T_{STG}$ )	-65°C to +150°C	Common Mode Input Voltage				
Max Junction Temperature ( $T_J$ )	150°C	( $V_{IC}$ )	(0V + $ V_{ID} /2$ ) to ( $V_{CC} -  V_{ID} /2$ )			
Lead Temperature ( $T_L$ ) (Soldering, 10 seconds)	260°C					
ESD (Human Body Model)	7000V					
ESD (Machine Model)	300V					
<b>Note 1:</b> The "Absolute Maximum Ratings": are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature and output/input loading variables. Fairchild does not recommend operation of circuits outside databook specification.						
<b>DC Electrical Characteristics</b>						
Over supply voltage and operating temperature ranges, unless otherwise specified						
Symbol	Parameter	Test Conditions	Min	Typ (Note 2)	Max	Units
$V_{TH}$	Differential Input Threshold HIGH	See Figure 1; $V_{IC} = +0.05V, +1.2V, \text{ or } (V_{CC} - 0.05V)$			100	mV
$V_{TL}$	Differential Input Threshold LOW	See Figure 1; $V_{IC} = +0.05V, +1.2V, \text{ or } (V_{CC} - 0.05V)$	-100			mV
$V_{IH}$	Input High Voltage (EN)		2.0		$V_{CC}$	V
$V_{IL}$	Input Low Voltage (EN)		GND		0.8	V
$V_{OD}$	Output Differential Voltage		250	330	450	mV
$\Delta V_{OD}$	$V_{OD}$ Magnitude Change from Differential LOW-to-HIGH	$R_L = 100 \Omega$ , Driver Enabled, See Figure 2			25	mV
$V_{OS}$	Offset Voltage		1.125	1.23	1.375	V
$\Delta V_{OS}$	Offset Magnitude Change from Differential LOW-to-HIGH				25	mV
$I_{OS}$	Short Circuit Output Current	$D_{OUT+} = 0V \text{ & } D_{OUT-} = 0V, \text{ Driver Enabled}$		-3.4	-6	mA
		$V_{OD} = 0V, \text{ Driver Enabled}$		$\pm 3.4$	$\pm 6$	mA
$I_{IN}$	Input Current (EN, $D_{INX+}$ , $D_{INX-}$ )	$V_{IN} = 0V \text{ to } V_{CC}$ , Other Input = $V_{CC}$ or 0V (for Differential Inputs)			$\pm 20$	$\mu A$
$I_{OFF}$	Power-Off Input or Output Current	$V_{CC} = 0V, V_{IN} \text{ or } V_{OUT} = 0V \text{ to } 3.6V$			$\pm 20$	$\mu A$
$I_{CC2}$	Disabled Power Supply Current	Drivers Disabled		3.2	5.5	mA
$I_{CC}$	Power Supply Current	Drivers Enabled, Any Valid Input Condition		9.3	13.5	mA
$I_{OZ}$	Disabled Output Leakage Current	Driver Disabled, $D_{OUT+} = 0V \text{ to } 3.6V$ or $D_{OUT-} = 0V \text{ to } 3.6V$			$\pm 20$	$\mu A$
$V_{IC}$	Common Mode Voltage Range	$ V_{ID}  = 100 \text{ mV to } V_{CC}$	0V + $ V_{ID} /2$		$V_{CC} - ( V_{ID} /2)$	V
$C_{IN}$	Input Capacitance	EN Input Data Input	2.2			pF
$C_{OUT}$	Output Capacitance		2.0			
			2.6			pF

**Note 2:** All typical values are at  $T_A = 25^\circ\text{C}$  and with  $V_{CC} = 3.3V$ .

## AC Electrical Characteristics

Over supply voltage and operating temperature ranges, unless otherwise specified

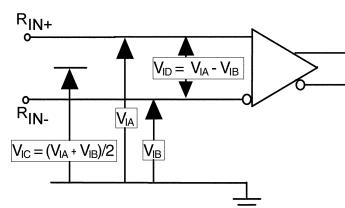
Symbol	Parameter	Test Conditions	Min	Typ (Note 3)	Max	Units
$t_{PLHD}$	Differential Propagation Delay LOW-to-HIGH		0.75	1.1	1.75	ns
$t_{PHLD}$	Differential Propagation Delay HIGH-to-LOW		0.75	1.1	1.75	ns
$t_{TLHD}$	Differential Output Rise Time (20% to 80%)		0.29	0.40	0.58	ns
$t_{THLD}$	Differential Output Fall Time (80% to 20%)		0.29	0.40	0.58	ns
$t_{SK(P)}$	Pulse Skew $ t_{PLH} - t_{PHL} $	See Figure 3 and Figure 4	0.01	0.2	0.5	ns
$t_{SK(PP)}$	Part-to-Part Skew (Note 4)				0.5	ns
$f_{MAX}$	Maximum Frequency (Note 5)(Note 6)		400	800		MHz
$t_{PZHD}$	Differential Output Enable Time from Z to HIGH			2.1	5	ns
$t_{PZLD}$	Differential Output Enable Time from Z to LOW	$R_L = 100 \Omega, C_L = 5 \text{ pF}$ , See Figure 2 and Figure 3		2.3	5	ns
$t_{PHZD}$	Differential Output Disable Time from HIGH to Z			1.5	5	ns
$t_{PLZD}$	Differential Output Disable Time from LOW to Z			1.8	5	ns
$t_{DJ}$	LVDS Data Jitter, Deterministic	$V_{ID} = 300 \text{ mV}$ , PRBS = $2^{23} - 1$ , $V_{IC} = 1.2 \text{ V}$ at 800 Mbps		85	135	ps
$t_{RJ}$	LVDS Clock Jitter, Random (RMS)	$V_{ID} = 300 \text{ mV}$ $V_{IC} = 1.2 \text{ V}$ at 400 MHz		2.1	3.5	ps

**Note 3:** All typical values are at  $T_A = 25^\circ\text{C}$  and with  $V_{CC} = 3.3\text{V}$ ,  $V_{ID} = 300\text{mV}$ ,  $V_{IC} = 1.2\text{V}$  unless otherwise specified.

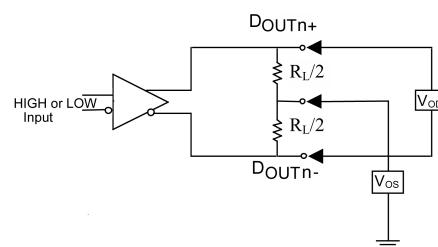
**Note 4:**  $t_{SK(PP)}$  is the magnitude of the difference in differential propagation delay times between identical channels of two devices switching in the same direction (either LOW-to-HIGH or HIGH-to-LOW) when both devices operate with the same supply voltage, same temperature, and have identical test circuits.

**Note 5:** Passing criteria for maximum frequency is the output  $V_{OD} > 200 \text{ mV}$  and the duty cycle is 45% to 55% with all channels switching.

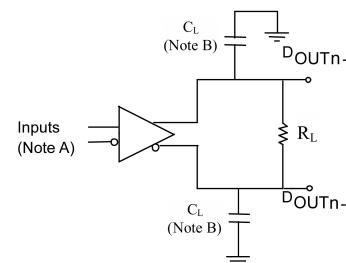
**Note 6:** Output loading is transmission line environment only;  $C_L$  is  $< 1 \text{ pF}$  of stray test fixture capacitance.



**FIGURE 1. Differential Receiver Voltage Definitions and Propagation Time Test Circuit**



**FIGURE 2. Differential Driver DC Test Circuit**

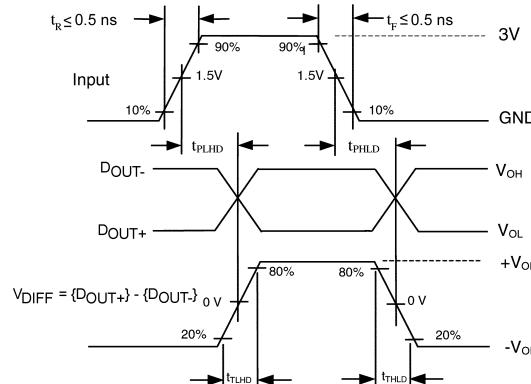


**Note A:** All LVDS input pulses have frequency = 10MHz,  $t_R$  or  $t_F \leq 0.5 \text{ ns}$

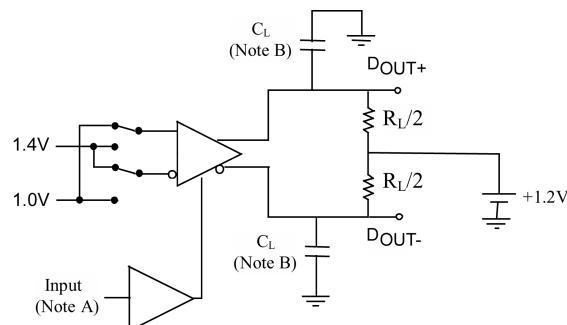
**Note B:**  $C_L$  includes all probe and test fixture capacitances

**FIGURE 3. Differential Driver Propagation Delay and Transition Time Test Circuit**

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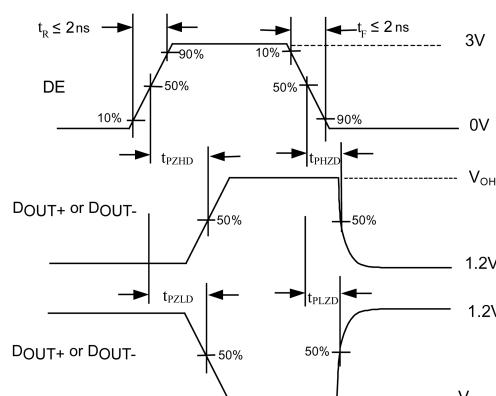


**FIGURE 4. AC Waveforms**



Note A: All LVTTI input pulses have frequency = 10 MHz,  $t_R$  or  $t_F \leq 2$  ns  
Note B:  $C_L$  includes all probe and test fixture capacitances

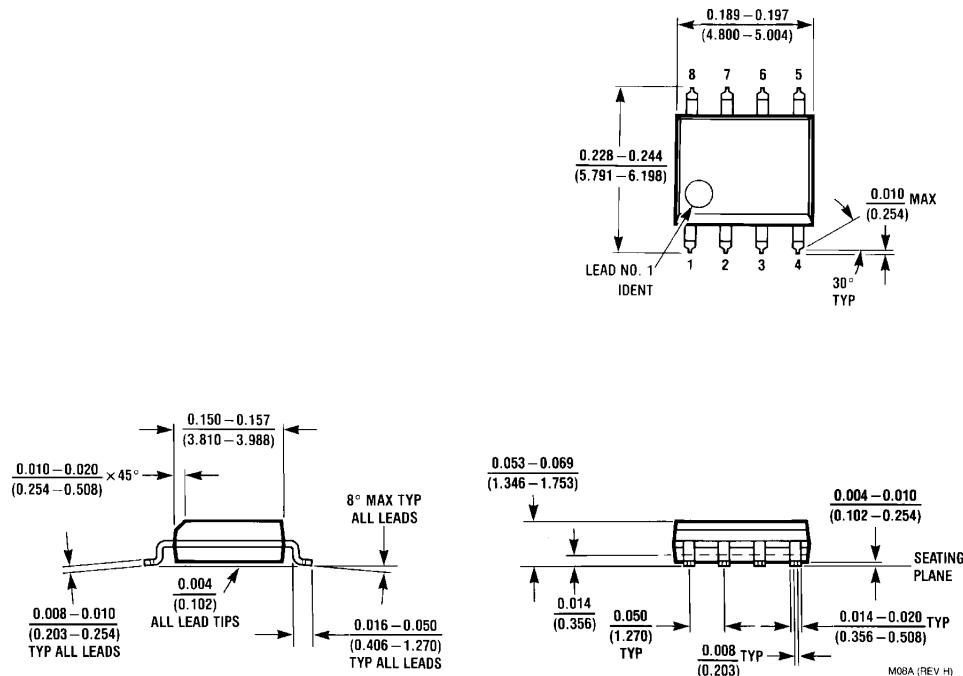
**FIGURE 5. Differential Driver Enable and Disable Test Circuit**



**FIGURE 6. Enable and Disable AC Waveforms**

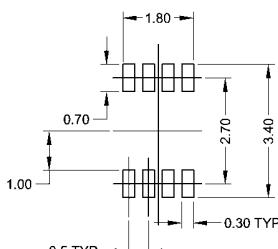
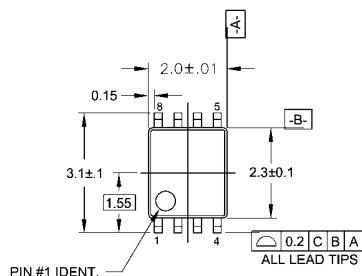
**FIN1101**

**Physical Dimensions** inches (millimeters) unless otherwise noted

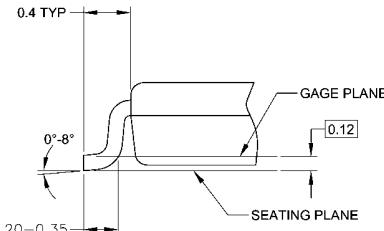
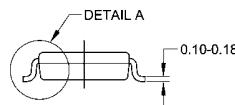
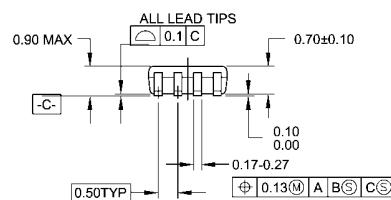


**FIN1101 LVDS Single Port High Speed Repeater**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



LAND PATTERN RECOMMENDATION



NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-187
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES PER ANSI Y14.5M, 1982.

DETAIL A

MAB08AREVC

8-Lead US8, JEDEC MO-187, Variation CA 3.1mm Wide  
Package Number MAB08A

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